

**Notice of References Cited**Application/Control No.  
**09/672,738**Applicant(s)/Patent Under Reexam  
**Yukio Tanaka**Examiner  
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**2675**

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	4,830,466	5/1989	Matsushita et al.	349	143
B	5,745,093	4/1998	Tsuzuki et al.	345	103
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**NON-PATENT DOCUMENTS**

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